

MOS FIELD EFFECT TRANSISTOR

NP82N055ELE, NP82N055KLE

NP82N055CLE, NP82N055DLE, NP82N055MLE, NP82N055NLE

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

These products are N-channel MOS Field Effect Transistors designed for high current switching applications.

ORDERING INFORMATION

PART NUMBER	LEAD PLATING	PACKING	PACKAGE	
NP82N055ELE-E1-AY Note1, 2			TO-263 (MP-25ZJ) typ. 1.4 g	
NP82N055ELE-E2-AY Note1, 2	Dura Ca (Tia)	Tana 200 n/raal		
NP82N055KLE-E1-AY Note1	Pure Sn (Tin)	Tape 800 p/reel	TO 200 (MD 257K) has 4.5 a	
NP82N055KLE-E2-AY Note1			TO-263 (MP-25ZK) typ. 1.5 g	
NP82N055CLE-S12-AZ Note1, 2	Sn-Ag-Cu		TO-220 (MP-25) typ. 1.9 g	
NP82N055DLE-S12-AY Note1, 2		Tube 50 p/tube	TO-262 (MP-25 Fin Cut) typ. 1.8 g	
NP82N055MLE-S18-AY Note1	Pure Sn (Tin)		TO-220 (MP-25K) typ. 1.9 g	
NP82N055NLE-S18-AY Note1			TO-262 (MP-25SK) typ. 1.8 g	

Notes 1. Pb-free (This product does not contain Pb in the external electrode.)

2. Not for new design

FEATURES

- Channel temperature 175 degree rated
- Super low on-state resistance

 $R_{DS(on)1} = 8.4 \text{ m}\Omega$ MAX. (Vgs = 10 V, ID = 41 A)

 $R_{DS(on)2}$ = 11 m Ω MAX. (VGS = 5.0 V, ID = 41 A)

 $R_{DS(on)3} = 12 \text{ m}\Omega$ MAX. (Vgs = 4.5 V, ID = 41 A)

· Low input capacitance

Ciss = 4400 pF TYP.

• Built-in gate protection diode

(TO-220)



(TO-262)





The information in this document is subject to change without notice. Before using this document, please confirm that this is the latest version.

Not all products and/or types are available in every country. Please check with an NEC Electronics sales representative for availability and additional information.

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	55	V
Gate to Source Voltage (V _{DS} = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C) Note1	I _{D(DC)}	±82	Α
Drain Current (Pulse) Note2	I _{D(pulse)}	±300	Α
Total Power Dissipation (Tc = 25°C)	Рт	163	W
Total Power Dissipation (T _A = 25°C)	Рт	1.8	W
Channel Temperature	Tch	175	°C
Storage Temperature	Tstg	-55 to +175	°C
Single Avalanche Current Note3	las	72/50/17	Α
Single Avalanche Energy Note3	Eas	51/250/289	mJ

 $\textbf{Notes 1.} \ \ \textbf{Calculated constant current according to MAX. allowable channel temperature.}$

- **2.** PW \leq 10 μ s, Duty cycle \leq 1%
- 3. Starting T_{ch} = 25°C, V_{DD} = 28 V, R_G = 25 Ω , V_{GS} = 20 \rightarrow 0 V (see Figure 4.)

THERMAL RESISTANCE

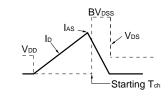
Channel to Case Thermal Resistance	Rth(ch-C)	0.92	°C/W
Channel to Ambient Thermal Resistance	Rth(ch-A)	83.3	°C/W

ELECTRICAL CHARACTERISTICS (TA = 25°C)

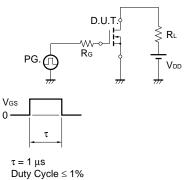
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	Ipss	V _{DS} = 55 V, V _{GS} = 0 V			10	μΑ
Gate Leakage Current	Igss	V _{GS} = ±20 V, V _{DS} = 0 V			±10	μΑ
Gate to Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	1.5	2.0	2.5	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 41 A	24	50		S
Drain to Source On-state Resistance	RDS(on)1	V _G S = 10 V, I _D = 41 A		6.7	8.4	mΩ
	RDS(on)2	V _{GS} = 5.0 V, I _D = 41 A		7.9	11	mΩ
	RDS(on)3	V _{GS} = 4.5 V, I _D = 41 A		8.4	12	mΩ
Input Capacitance	Ciss	V _{DS} = 25 V,		4400	6600	pF
Output Capacitance	Coss	V _{GS} = 0 V,		550	830	pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		270	490	pF
Turn-on Delay Time	td(on)	V _{DD} = 28 V, I _D = 41 A,		28	61	ns
Rise Time	tr	V _{GS} = 10 V,		16	39	ns
Turn-off Delay Time	td(off)	$R_G = 1 \Omega$		92	180	ns
Fall Time	tr			18	45	ns
Total Gate Charge	Q _{G1}	I _D = 82 A, V _{DD} = 44 V, V _{GS} = 10 V		80	120	nC
	Q _{G2}	V _{DD} = 44 V,		45	68	nC
Gate to Source Charge	Q _{GS}	V _{GS} = 5.0 V,		15		nC
Gate to Drain Charge	Q _{GD}	I _D = 82 A		24		nC
Body Diode Forward Voltage	V _{F(S-D)}	I _F = 82 A, V _{GS} = 0 V		1.0		V
Reverse Recovery Time	trr	I _F = 82 A, V _{GS} = 0 V,		47		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/μs		66		nC

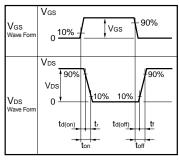
TEST CIRCUIT 1 AVALANCHE CAPABILITY

$\begin{array}{c} \text{D.U.T.} \\ \text{Rg} = 25 \Omega \\ \text{Vgs} = 20 \rightarrow 0 \text{ V} \end{array}$



TEST CIRCUIT 2 SWITCHING TIME



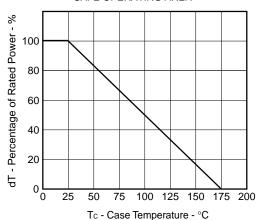


TEST CIRCUIT 3 GATE CHARGE

$$\begin{array}{c|c} D.U.T. \\ I_G = 2 \text{ mA} & I_{-} \\ \hline \\ PG. & \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ \end{array} \begin{array}{c} S_{DU} \\ \hline \\ \end{array} \begin{array}{c} S_{DU} \\ \hline \end{array} \begin{array}{c} S_{DU} \\ \hline \\ \end{array} \begin{array}{c} S_{DU} \\ \hline \\$$

TYPICAL CHARACTERISTICS (TA = 25°C)

Figure1. DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA



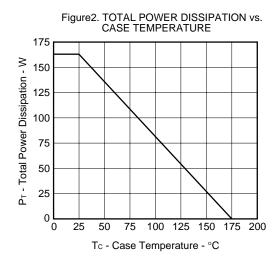


Figure.3 FORWARD BIAS SAFE OPERATING AREA

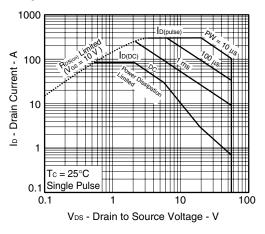


Figure4. SINGLE AVALANCHE ENERGY DERATING FACTOR

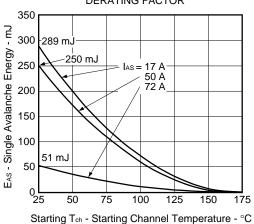
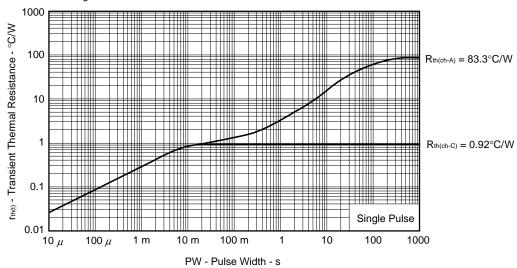
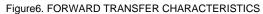


Figure 5. TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH





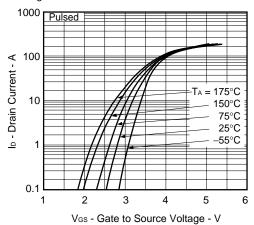


Figure8. FORWARD TRANSFER ADMITTANCE vs. DRAIN CURRENT

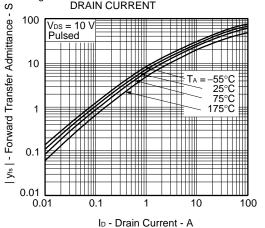


Figure 10. DRAIN TO SOURCE ON-STATE RESISTANCE vs. DRAIN CURRENT

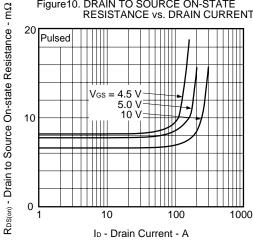


Figure7. DRAIN CURRENT vs.
DRAIN TO SOURCE VOLTAGE

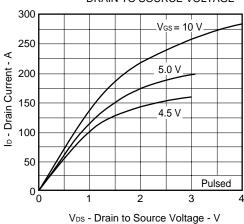


Figure9. DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

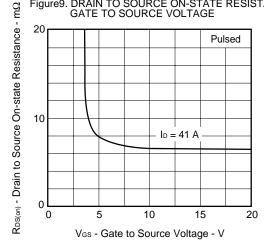


Figure 11. GATE TO SOURCE THRESHOLD VOLTAGE vs. CHANNEL TEMPERATURE

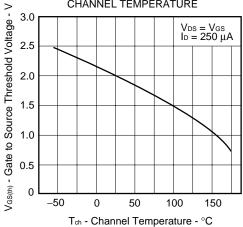


Figure 12. DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE

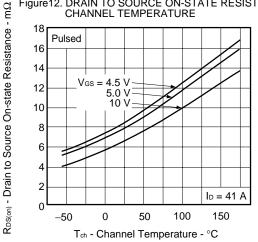


Figure 13. SOURCE TO DRAIN DIODE FORWARD VOLTAGE

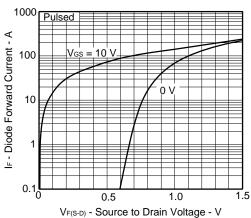


Figure 14. CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE

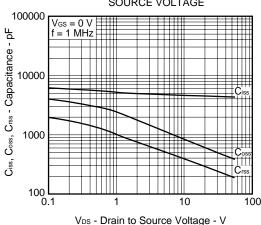


Figure 15. SWITCHING CHARACTERISTICS

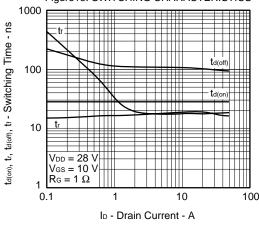


Figure 16. REVERSE RECOVERY TIME vs. DIODE FORWARD CURRENT

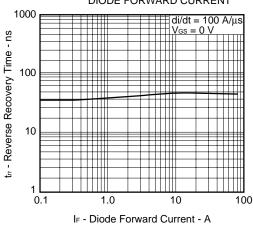
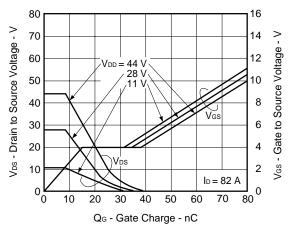
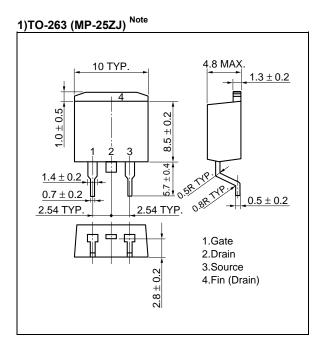
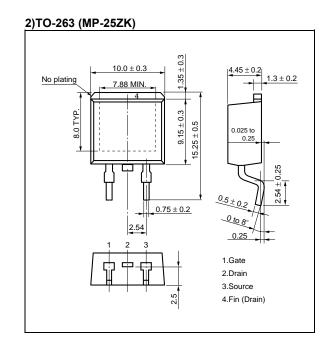


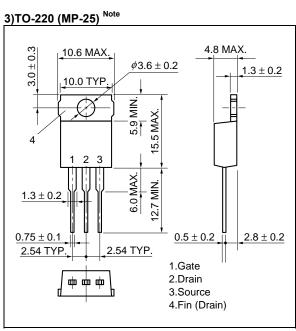
Figure 17. DYNAMIC INPUT/OUTPUT CHARACTERISTICS

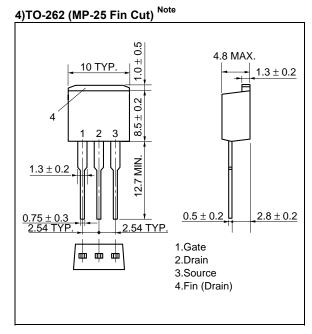


<R> PACKAGE DRAWINGS (Unit: mm)

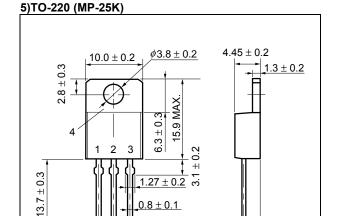








Note Not for new design



2.54 TYP.

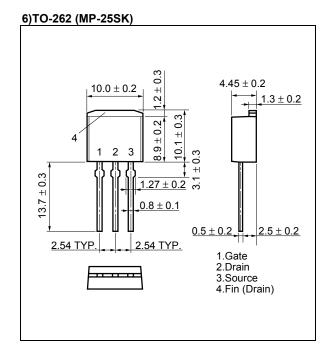
 0.5 ± 0.2

1.Gate

2.Drain

3.Source 4.Fin (Drain)

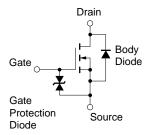
 2.5 ± 0.2



EQUIVALENT CIRCUIT

...

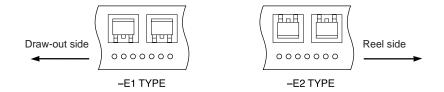
2.54 TYP.



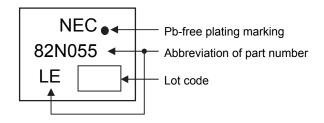
Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

<R> TAPE INFORMATION

There are two types (-E1, -E2) of taping depending on the direction of the device.



<R> MARKING INFORMATION



<R> RECOMMENDED SOLDERING CONDITIONS

These products should be soldered and mounted under the following recommended conditions.

For soldering methods and conditions other than those recommended below, please contact an NEC Electronics sales representative.

For technical information, see the following website.

Semiconductor Device Mount Manual (http://www.necel.com/pkg/en/mount/index.html)

Soldering Method	Soldering Conditions	Recommended Condition Symbol	
Infrared reflow	Maximum temperature (Package's surface temperature): 260°C or below		
MP-25ZJ, MP-25ZK	Time at maximum temperature: 10 seconds or less		
	Time of temperature higher than 220°C: 60 seconds or less	JD00 00 0	
	Preheating time at 160 to 180°C: 60 to 120 seconds	IR60-00-3	
	Maximum number of reflow processes: 3 times		
	Maximum chlorine content of rosin flux (percentage mass): 0.2% or less		
Wave soldering	Maximum temperature (Solder temperature): 260°C or below		
MP-25, MP-25K, MP-25SK,	Time: 10 seconds or less	THDWS	
MP-25 Fin Cut	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		
Partial heating	Maximum temperature (Pin temperature): 350°C or below		
MP-25ZJ, MP-25ZK,	Time (per side of the device): 3 seconds or less	P350	
MP-25K, MP-25SK	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		
Partial heating	Maximum temperature (Pin temperature): 300°C or below		
MP-25, MP-25 Fin Cut	Time (per side of the device): 3 seconds or less	P300	
	Maximum chlorine content of rosin flux: 0.2% (wt.) or less		

Caution Do not use different soldering methods together (except for partial heating).

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 - "Special": Transportation equipment (automobiles, trains, ships, etc.), traffic control systems, anti-disaster systems, anti-crime systems, safety equipment and medical equipment (not specifically designed for life support).
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